

Notice of References Cited

Application/Control No.

10/779,904

Applicant(s)/Patent Under

Reexamination

ISHIDA ET AL.

Examiner

OSCAR A. LOUIE

Art Unit

2436

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,483,170	01-1996	Beasley et al.	324/537
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	"IDD pulse response testing applied to complex CMOS ICs," Beasley et al., Test Conference, 1997. Proceedings., International, IEEE, 11/1-6/1997.
V	"Defect detection with transient current testing and its potential for deep submicron CMOS ICs," Sachdev et al., Test Conference, 1998. Proceedings., International, 18-23 Oct 1998.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.